

Sampling



Provides lot-based sampling as well as sub-material sampling at metrology steps

Overview

In many cases it's not practical to inspect or measure every single lot; and even in an inspection or metrology step, it's not practical to inspect or measure every single unit of a lot. The Sampling module provides the capability to implement sampling strategies by pre-defining 1) which materials must

go through an inspection or metrology step based on time or counters; and 2) which sub-materials to be measured at an inspection or metrology step. Once the sampling strategy is defined, the system will execute and enforce it automatically.

My Sampling Plan (Active)

DETAILS

Sampling Plan

Name: My Sampling Plan
Description: My Sampling Plan
Type: Standard
Universal State: Active

Details

Type: CounterBased
Counter Frequency: 10

CONTEXT

Refresh Manage

Context Information (1)

ORDER	NAME	DESCRIPTION	CONTEXT
1	Resource	Resource	MaterialResource

Rows per page: 10 Page 1 of 1 (1 records)

Figure 1 Sampling Plan example



Critical
manufacturing 10.2

Disclaimer · The information contained in this document represents the current view of Critical Manufacturing on the issues discussed as of the date of publication. Because Critical Manufacturing must respond to changing market conditions, it should not be interpreted to be a commitment on the part of Critical Manufacturing, and Critical Manufacturing cannot guarantee the accuracy of any information presented after the date of publication. This document is for informational purposes only. Critical Manufacturing makes no warranties, express, implied or statutory, as to the information herein contained.

contact@criticalmanufacturing.com · www.criticalmanufacturing.com

Key Features

- Support for static and dynamic inspection plans, including AQL, supporting:
 - In-process measurements as well as measurements that are performed in different inspection stations (e.g.: a lab)
 - Variable and Attribute results
 - The definition and capture of measurement instruments, ensuring that they are calibrated and that they cover the required range and have the required precision
 - Automatic severity switching rules
- Support for lot-based sampling strategies based on flexible contexts that can be:
 - Counter based (e.g.: every 10th lot of a certain product)
 - Time based (e.g.: one lot from a certain equipment every 8 hours)
- Support for sub-material selection at a metrology step, for example to measure the top, middle and bottom wafers and in that particular sequence. The sub-materials to be measured can be defined manually or by a business rule (system or user-defined).
- Integration with Material Tracking and transparent to the user.

Benefits

- Improved process control
- Reduction of costs
- Reduction in the opportunity for errors

Post Data to Data Collection


LOT-01 (InProcess) / MOSRM8HQ (MOSRM8HQ Product) / Inspection / 100 Kg

< Width (Variable)

WIDTH (VARIABLE)	
* Sample 1	999 mm
* Sample 2	999.8 mm
* Sample 3	1000.1 mm
* Sample 4	998.8 mm
* Sample 5	1000.4 mm

Last entered value: Width > Sample 5 > 1000.4 mm

Measure the width of the scalpel at the thinnest point.



Width > Sample 5

999	1,000	1,001	
1000.4 mm			
7	8	9	C
4	5	6	Del
1	2	3	OK
+/-	0	.	

Comments:

Cancel
Post

Figure 2 Inspection example